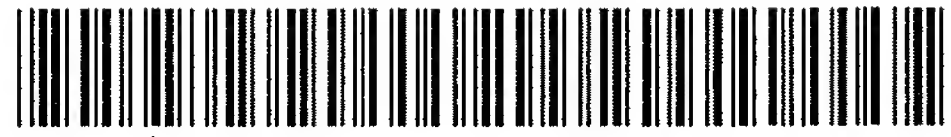


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(54) Lithographic apparatus and device manufacturing method

(57) A lithographic projection apparatus in which the projection system comprises a plurality of optical elements or sensors mounted on a frame. The frame is made of a glass ceramic material with a coefficient of thermal expansion of less than or approximately equal to $0.1 \times 10^{-6} \text{ K}^{-1}$ thereby avoiding the need for expensive cooling systems and/or predictive temperature compensation.

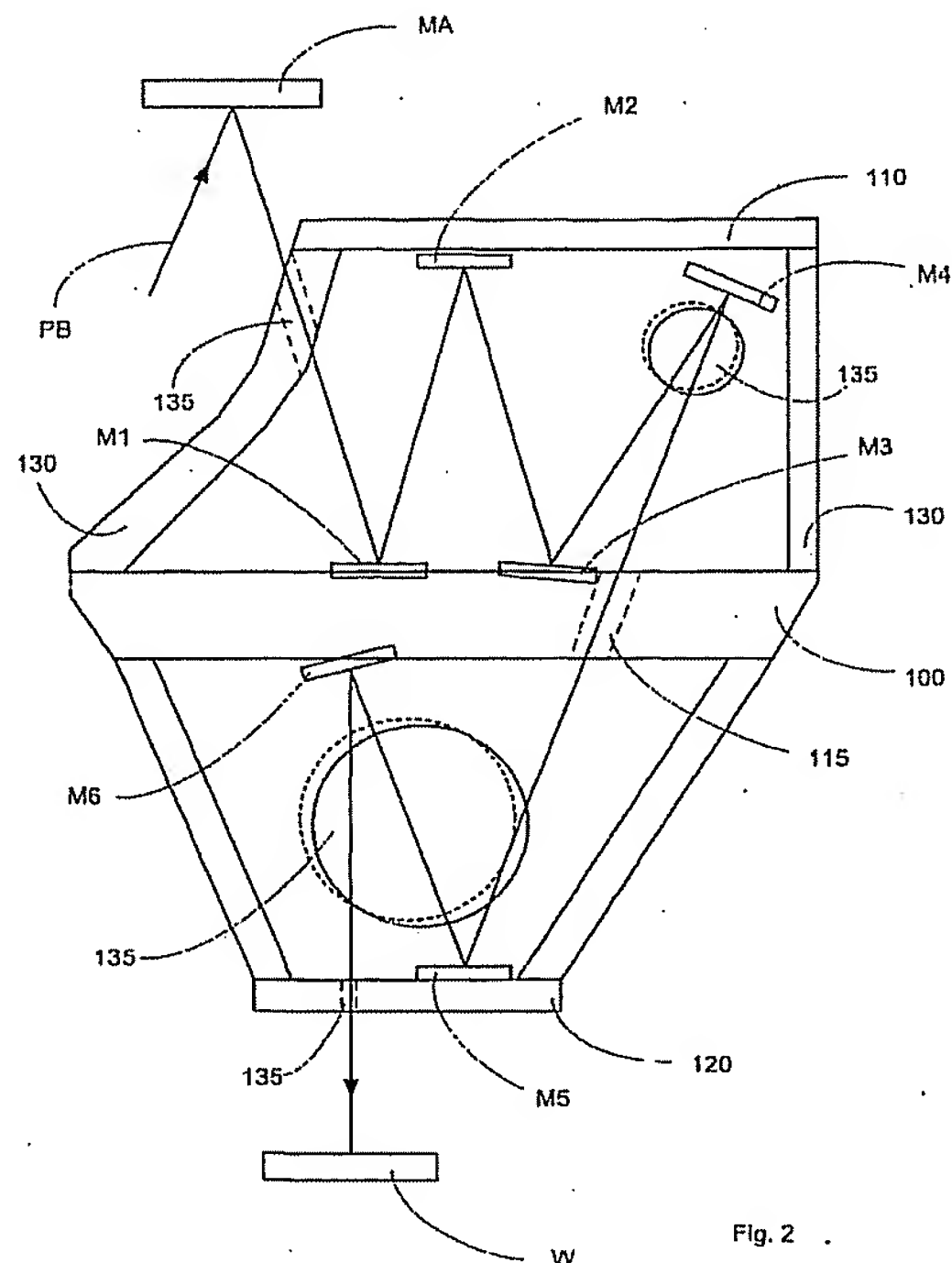


Fig. 2

Description

[0001] The present invention relates to a lithographic projection apparatus comprising:

- a radiation system for supplying a projection beam of radiation;
- a support structure for supporting patterning means, the patterning means serving to pattern the projection beam according to a desired pattern;
- a substrate table for holding a substrate;
- a projection system for projecting the patterned beam onto a target portion of the substrate; and

a frame supporting a plurality of optical elements of said projection system and/or components of sensors,

[0002] The term "patterning means" as here employed should be broadly interpreted as referring to means that can be used to endow an incoming radiation beam with a patterned cross-section, corresponding to a pattern that is to be created in a target portion of the substrate; the term "light valve" can also be used in this context. Generally, the said pattern will correspond to a particular functional layer in a device being created in the target portion, such as an integrated circuit or other device (see below). Examples of such patterning means include:

- A mask. The concept of a mask is well known in lithography, and it includes mask types such as binary, alternating phase-shift, and attenuated phase-shift, as well as various hybrid mask types. Placement of such a mask in the radiation beam causes selective transmission (in the case of a transmissive mask) or reflection (in the case of a reflective mask) of the radiation impinging on the mask, according to the pattern on the mask. In the case of a mask, the support structure will generally be a mask table, which ensures that the mask can be held at a desired position in the incoming radiation beam, and that it can be moved relative to the beam if so desired.
- A programmable mirror array. One example of such a device is a matrix-addressable surface having a viscoelastic control layer and a reflective surface. The basic principle behind such an apparatus is that (for example) addressed areas of the reflective surface reflect incident light as diffracted light, whereas unaddressed areas reflect incident light as undiffracted light. Using an appropriate filter, the said undiffracted light can be filtered out of the reflected beam, leaving only the diffracted light behind; in this manner, the beam becomes patterned according to the addressing pattern of the matrix-addressable surface. An alternative embodiment of a programmable mirror array employs a matrix arrangement of tiny mirrors, each of which can be individually tilted about an axis by applying a suitable localized electric field, or by employing piezoelectric actuation means. Once again, the mirrors are matrix-addressable, such that addressed mirrors will reflect an incoming radiation beam in a different direction to unaddressed mirrors; in this manner, the reflected beam is patterned according to the addressing pattern of the matrix-addressable mirrors. The required matrix addressing can be performed using suitable electronic means. In both of the situations described hereabove, the patterning means can comprise one or more programmable mirror arrays. More information on mirror arrays as here referred to can be gleaned, for example, from United States Patents US 5,296,891 and US 5,523,193, and PCT patent applications WO 98/38597 and WO 98/33096, which are incorporated herein by reference. In the case of a programmable mirror array, the said support structure may be embodied as a frame or table, for example, which may be fixed or movable as required.
- A programmable LCD array. An example of such a construction is given in United States Patent US 5,229,872, which is incorporated herein by reference. As above, the support structure in this case may be embodied as a frame or table, for example, which may be fixed or movable as required.

For purposes of simplicity, the rest of this text may, at certain locations, specifically direct itself to examples involving a mask and mask table; however, the general principles discussed in such instances should be seen in the broader context of the patterning means as hereabove set forth.

[0003] Lithographic projection apparatus can be used, for example, in the manufacture of integrated circuits (ICs). In such a case, the patterning means may generate a circuit pattern corresponding to an individual layer of the IC, and this pattern can be imaged onto a target portion (e.g. comprising one or more dies) on a substrate (silicon wafer) that has been coated with a layer of radiation-sensitive material (resist). In general, a single wafer will contain a whole network of adjacent target portions that are successively irradiated via the projection system, one at a time. In current apparatus, employing patterning by a mask on a mask table, a distinction can be made between two different types of machine. In one type of lithographic projection apparatus, each target portion is irradiated by exposing the entire mask pattern onto the target portion in one go; such an apparatus is commonly referred to as a wafer stepper. In an alternative apparatus — commonly referred to as a step-and-scan apparatus — each target portion is irradiated by progressively scanning the mask pattern under the projection beam in a given reference direction (the "scanning" direction) while synchronously scanning the substrate table parallel or anti-parallel to this direction; since, in general, the projection system will have a magnification factor M (generally < 1), the speed V at which the substrate table is scanned will be

a factor M times that at which the mask table is scanned. More information with regard to lithographic devices as here described can be gleaned, for example, from US 6,046,792, incorporated herein by reference.

[0004] In a manufacturing process using a lithographic projection apparatus, a pattern (e.g. in a mask) is imaged onto a substrate that is at least partially covered by a layer of radiation-sensitive material (resist). Prior to this imaging step, the substrate may undergo various procedures, such as priming, resist coating and a soft bake. After exposure, the substrate may be subjected to other procedures, such as a post-exposure bake (PEB), development, a hard bake and measurement/inspection of the imaged features. This array of procedures is used as a basis to pattern an individual layer of a device, e.g. an IC. Such a patterned layer may then undergo various processes such as etching, ion-implantation (doping), metallization, oxidation, chemo-mechanical polishing, etc., all intended to finish off an individual layer. If several layers are required, then the whole procedure, or a variant thereof, will have to be repeated for each new layer. Eventually, an array of devices will be present on the substrate (wafer). These devices are then separated from one another by a technique such as dicing or sawing, whence the individual devices can be mounted on a carrier, connected to pins, etc. Further information regarding such processes can be obtained, for example, from the book "Microchip Fabrication: A Practical Guide to Semiconductor Processing", Third Edition, by Peter van Zant, McGraw Hill Publishing Co., 1997, ISBN 0-07-067250-4, incorporated herein by reference.

[0005] For the sake of simplicity, the projection system may hereinafter be referred to as the "lens"; however, this term should be broadly interpreted as encompassing various types of projection system, including refractive optics, reflective optics, and catadioptric systems, for example. The radiation system may also include components operating according to any of these design types for directing, shaping or controlling the projection beam of radiation, and such components may also be referred to below, collectively or singularly, as a "lens". Further, the lithographic apparatus may be of a type having two or more substrate tables (and/or two or more mask tables). In such "multiple stage" devices the additional tables may be used in parallel, or preparatory steps may be carried out on one or more tables while one or more other tables are being used for exposures. Dual stage lithographic apparatus are described, for example, in US 5,969,441 and WO 98/40791, incorporated herein by reference.

[0006] The projection system of a lithographic projection apparatus which uses a beam of ultra-violet radiation with a wavelength of, for example, 248 nm, typically comprises a plurality of refractive optical elements mounted to a frame. The refractive optical elements must be positioned accurately relative to the beam and to one another and must be isolated from vibrations of the base member. These conditions can be met by making the frame to which the optical elements are mounted of Invar (TM) (a cobalt containing steel). Invar (TM) is a metal with a Young's Modulus, E, of about 140 000 MN/m². The advantage of this material is that it is easy to machine into the relatively complicated shapes required of the frame of the projection system and, as a metal, can easily be manufactured in separate parts and joined together by welding or other joining techniques used for joining metals. The high Young's Modulus, E, of Invar (TM) means that a frame which has a high mechanical stiffness to prevent mechanical vibrations being transmitted to the optical elements can easily be designed. A further advantage of Invar (TM) over, for example, stainless steel (which has also been used) is that it has a relatively low coefficient of thermal expansion thereby resulting in a projection system for a lithographic projection apparatus which is temperature stable. The coefficient of thermal expansion of Invar (TM) is about $1 \times 10^{-6} \text{ K}^{-1}$ which is about the lowest of any known metal.

[0007] To meet the ever-present demand for imaging features of reduced size, it is necessary to reduce the wavelength of radiation used for the projection beam. Thus, improved resolution requires the development of lithographic projection apparatus making use of extreme ultra-violet radiation (EUV) (i.e. with a wavelength in the range of 5-20 nm). An EUV lithography apparatus must use mirrors in the projection system because no material suitable for forming refractive optical elements for EUV is known and the beam must be kept in vacuum to avoid contamination and attenuation of the beam. The positioning requirements of the optical elements of EUV lithography apparatus are considerably more stringent than those of ultra-violet lithography apparatus because: (a) the smaller wavelength of radiation which is used, (b) reflective rather than refractive optical elements are used, and (c) the increased resolution, i.e. the smaller size of the features to be imaged. Under these circumstances, the required positioning accuracy increases to the order of 10 nm or so.

[0008] Unfortunately, with the increased positioning accuracy required in EUV lithography apparatus it has been found that a frame made of Invar (TM) either requires cooling to maintain the position of the optical elements within the desired positional accuracy or requires predictive temperature compensating positioning control, which is complicated and expensive.

[0009] It is an object of the present invention to provide a projection system which meets the requirements for EUV lithography apparatus.

[0010] This and other objects are achieved according to the invention in a lithographic apparatus as specified in the opening paragraph, characterized in that said frame is made of a glass ceramic material with a coefficient of thermal expansion of less than or approximately equal to $0.1 \times 10^{-6} \text{ K}^{-1}$.

[0011] Thus, the need for either complicated predictive temperature compensation positioning means for each optical element or the need for heavy, bulky and intricate cooling systems is avoided without compromising on the effect of

temperature fluctuations on the stability of the position of the optical elements mounted on the frame.

[0012] Traditionally glass ceramic materials have been seen as not being suitable for use as structural elements in a lithography apparatus partly because of the difficulty in machining and joining them compared metals and partly because of their lower stiffness compared to metals. They are also brittle and expensive and have low resistance to shock. However, careful design allows such materials to be used despite their Young's Modulus, E , being somewhat lower than that of stainless steel, Invar (TM) or other metals which have previously been used for structural elements in lithography apparatus. The term "glass ceramic" is a term used in the field to describe a material which is a combination of a glass and a ceramic but which is neither a glass nor a ceramic.

[0013] There are further surprising advantages to using glass ceramics. The first of these is their large emission coefficient for electromagnetic radiation in the infrared range. This coefficient is at least a factor of 5-10 times larger than that for stainless steel or Invar (TM). This means that glass ceramics adapt more easily to the surrounding temperature in (the vacuum) of an EUV apparatus. Thus, the temperature of the frame of the present invention is more easily controlled if such control is found to be necessary (for instance if the sensing means on the frame are temperature sensitive). Another advantage is that glass ceramics have better vacuum compatibility than metals as unlike metals they do not tend to absorb molecules on their surface which can be detrimental to a vacuum when they de-absorb.

[0014] Preferably the material has a Young's Modulus, E , of at least 60,000 MN/m². With such a material, a frame can be built which does not suffer from parasitic vibrations typically present in a lithography apparatus by careful design. Materials from which the frame may be built to the design requirements include ULE (TM) glass (manufactured by Corning Incorporated, 1 River Front Plaza, Corning, NY 14831), Zerodur (TM) (manufactured by Schott Glass, Hat-tenbergstraÙe 10 55120, Mainz, Germany) and Low CTE Cordierite (TM) (manufactured by Kyocera Corporation, 6 Takeda Tobadono-cho, Fushimi-ku, Kyoto 612-8501 Japan). Clearceram-Z (TM) (manufactured by Ohara group, Ashigara Optical Inc., 4292 Yoshidajima Ashigara Kami Gun, Knagawa, 228-0021, Japan) and the Russian glass ceramic Astrosital (TM) are variants of Zerodur (TM) and may also be used.

[0015] Preferably the frame comprises a first plate and at least one further plate, said plates being in spaced apart relationship and arranged such that surfaces of said plates face each other, said at least one further plate being attached to said first plate by stiffener elements thereby substantially to prevent flexing vibration of said plates. Such a construction is advantageous as the assembly of such a frame from a glass ceramic material with a coefficient of thermal expansion of less than $0.1 \times 10^{-6} \text{ K}^{-1}$ requires relatively few joints between members of the frame. The problem of using plates, namely their susceptibility to flexing vibration is overcome by the use of stiffener elements between the plates. Preferably the stiffener elements are provided between the edges of the plates but in any case at the corners. Preferably the optical elements are attached to the plates.

[0016] According to a further aspect of the invention there is provided a device manufacturing method comprising the steps of:

- providing a substrate that is at least partially covered by a layer of radiation-sensitive material;
- providing a projection beam of radiation using a radiation system;
- using patterning means to endow the projection beam with a pattern in its cross-section;
- using a plurality of optical elements to project the patterned beam of radiation onto a target portion of the layer of radiation-sensitive material,
- measuring the position of said optical elements using sensors,
- wherein said optical elements or said sensors are mounted on a frame, characterized in that said frame is made of a glass ceramic material with a coefficient of thermal expansion of less than or approximately equal to $0.1 \times 10^{-6} \text{ K}^{-1}$.

[0017] Although specific reference may be made in this text to the use of the apparatus according to the invention in the manufacture of ICs, it should be explicitly understood that such an apparatus has many other possible applications. For example, it may be employed in the manufacture of integrated optical systems, guidance and detection patterns for magnetic domain memories, liquid-crystal display panels, thin-film magnetic heads, etc. The skilled artisan will appreciate that, in the context of such alternative applications, any use of the terms "reticle", "wafer" or "die" in this text should be considered as being replaced by the more general terms "mask", "substrate" and "target portion", respectively.

[0018] In the present document, the terms "radiation" and "beam" are used to encompass all types of electromagnetic radiation, including ultraviolet radiation (e.g. with a wavelength of 365, 248, 193, 157 or 126 nm) and extreme ultraviolet (EUV) radiation (e.g. having a wavelength in the range 5-20 nm, especially around 13 nm), as well as particle beams, such as ion beams or electron beams.

[0019] An embodiment of the invention will now be described, by way of example only, with reference to the accompanying schematic drawings in which:

Figure 1 depicts a lithographic projection apparatus according to an embodiment of the invention; and Figure 2 is a cross-sectional view of a frame of the projection system of a lithographic projection apparatus according to the embodiment of the invention.

5 [0020] In the Figures, corresponding reference symbols indicate corresponding parts.

Embodiment 1

10 [0021] Figure 1 schematically depicts a lithographic projection apparatus according to a particular embodiment of the invention. The apparatus comprises:

- a radiation system Ex, IL, for supplying a projection beam PB of radiation (*e.g.* EUV radiation), which in this particular case also comprises a radiation source LA;
- a first object table (mask table) MT provided with a mask holder for holding a mask MA (*e.g.* a reticle), and connected to first positioning means PM for accurately positioning the mask with respect to item PL;
- a second object table (substrate table) WT provided with a substrate holder for holding a substrate W (*e.g.* a resist-coated silicon wafer), and connected to second positioning means PW for accurately positioning the substrate with respect to item PL;
- a projection system ("lens") PL (*e.g.* mirror system) for imaging an irradiated portion of the mask MA onto a target portion C (*e.g.* comprising one or more dies) of the substrate W using a plurality of optical elements *i.e.* mirrors. As here depicted, the apparatus is of a reflective type (*e.g.* has a reflective mask). However, in general, it may also be of a transmissive type, for example (*e.g.* with a transmissive mask). Alternatively, the apparatus may employ another kind of patterning means, such as a programmable mirror array of a type as referred to above.

25 [0022] The source LA (*e.g.* a laser-produced or discharge plasma source) produces a beam of radiation. This beam is fed into an illumination system (illuminator) IL, either directly or after having traversed conditioning means, such as a beam expander Ex, for example. The illuminator IL may comprise adjusting means AM for setting the outer and/or inner radial extent (commonly referred to as σ -outer and σ -inner, respectively) of the intensity distribution in the beam. In addition, it will generally comprise various other components, such as an integrator IN and a condenser CO. In this way, the beam PB impinging on the mask MA has a desired uniformity and intensity distribution in its cross-section.

30 [0023] It should be noted with regard to Figure 1 that the source LA may be within the housing of the lithographic projection apparatus (as is often the case when the source LA is a mercury lamp, for example), but that it may also be remote from the lithographic projection apparatus, the radiation beam which it produces being led into the apparatus (*e.g.* with the aid of suitable directing mirrors); this latter scenario is often the case when the source LA is an excimer laser. The current invention and Claims encompass both of these scenarios.

35 [0024] The beam PB subsequently intercepts the mask MA, which is held on a mask table MT. Having traversed the mask MA, the beam PB passes through the lens PL, which focuses the beam PB onto a target portion C of the substrate W. With the aid of the second positioning means PW (and interferometric measuring means IF), the substrate table WT can be moved accurately, *e.g.* so as to position different target portions C in the path of the beam PB. Similarly, the first positioning means PM can be used to accurately position the mask MA with respect to the path of the beam PB, *e.g.* after mechanical retrieval of the mask MA from a mask library, or during a scan. In general, movement of the object tables MT, WT will be realized with the aid of a long-stroke module (course positioning) and a short-stroke module (fine positioning), which are not explicitly depicted in Figure 1. However, in the case of a wafer stepper (as opposed to a step-and-scan apparatus) the mask table MT may just be connected to a short stroke actuator, or may be fixed.

45 [0025] The depicted apparatus can be used in two different modes:

1. In step mode, the mask table MT is kept essentially stationary, and an entire mask image is projected in one go (*i.e.* a single "flash") onto a target portion C. The substrate table WT is then shifted in the x and/or y directions so that a different target portion C can be irradiated by the beam PB;
2. In scan mode, essentially the same scenario applies, except that a given target portion C is not exposed in a single "flash". Instead, the mask table MT is movable in a given direction (the so-called "scan direction", *e.g.* the y direction) with a speed v , so that the projection beam PB is caused to scan over a mask image; concurrently, the substrate table WT is simultaneously moved in the same or opposite direction at a speed $V = Mv$, in which M is the magnification of the lens PL (typically, $M = 1/4$ or $1/5$). In this manner, a relatively large target portion C can be exposed, without having to compromise on resolution.

[0026] The optical elements of the projection system PL are mounted to a frame 10 which is illustrated in Figure 2.

[0027] The projection beam PB enters the projection system PL at the top of the frame 10 and exits at the bottom

of the frame 10 as illustrated. A plurality of optical elements (M1-M6) are supported, on the inside of the frame 10 which operate on the beam before the beam exits through the bottom of the frame 10. The optical elements of an EUV lithography apparatus are reflective and may be mounted to the frame 10 in a way as described in European Patent Application No. 01310781.8, incorporated herein by reference. The overall length of the frame 10 from where the projection beam PB enters to where it exits, is about 1.2 to 1.4 m and the distance from reticle to substrate about 1.5 m.

[0028] Previously (i.e. for lithographic projection apparatus using wavelengths of 248 or 193 nm) the frame 10 has been made of metal which is easily machined and can be assembled by welding. Stainless steel and more recently Invar (TM) have been used, Invar (TM) being particularly suitable because of its high stiffness and low (for a metal) coefficient of thermal expansion. However, it has been found that the thermal stability requirements of an EUV lithography apparatus cannot be met with such a frame without either thermal cooling or predictive temperature control.

[0029] According to the present invention it is proposed to make the frame 10 of a glass ceramic material with a coefficient of thermal expansion of less than $0.1 \times 10^{-6} \text{ K}^{-1}$. More preferably the material of the frame 10 has a coefficient of thermal expansion of less than 0.05×10^{-6} or $0.02 \times 10^{-6} \text{ K}^{-1}$. Unfortunately there are no presently known metals with a coefficient of thermal expansion in this range with the required stiffness and this is why the frame 10 is to be made of a glass ceramic material.

[0030] In order for the frame 10 to resist unwanted vibrations the frame 10 must be stiff. Theoretically the required stiffness of the frame can be achieved by many materials simply by making the individual members of the frame 10 thicker. However, if the material of the frame has a high Young's Modulus, E, and a low density this is preferable as the frame 10 may be made both lighter and less bulky.

[0031] It has been found that low coefficient of thermal expansion glass ceramic materials are best suited to the frame 10 of the present invention. Examples of such glass ceramics are ULE (TM), Zerodur (TM), and Cordierite (TM), Clearceram-Z (TM) or Astrosital (TM) (also known as Sital, Sital CO-115M and Astrosital) which are a combination of glass and ceramic but are neither glasses nor ceramics. The mechanical properties of those materials in comparison to mechanical properties of stainless steel and Invar (TM) are given in Table 1:

Table 1

| Material | E MN/m ² (MPa= 10^6 N/m ²) | Coefficient of Thermal Expansion K ⁻¹ | Density Kg/m ³ | Emission Coefficient for Electromagnetic Radiation in Infrared Range |
|-------------------|---|--|---------------------------|--|
| Stainless Steel | 200 000 | 10×10^{-6} | 7 700 | 0.1-0.2 |
| Invar (TM) | 140 000 | 1×10^{-6} | 8 100 | 0.1-0.25 |
| ULE (TM) | 70 000 | 0.01×10^{-6} | 2 210 | 0.8 |
| Zerodur (TM) | 90 000 | $<0.05 \times 10^{-6}$ | 2 500 | 0.8 |
| Cordierite (TM) | 140 000 | 0.05×10^{-6} | 2 530 | 0.8 |
| Astrosital (TM) | 90 000 | 0.03×10^{-6} | 2 460 | 0.8 |
| Clearceram-Z (TM) | 90 300 | 0.03×10^{-6} | 2 550 | 0.8 |

[0032] ULE (TM) is a titanium silicate glass ceramic manufactured by flame hydrolysis. The material is based on SiO₂ with TiO₂ present in a quantity of about 7 wt%. Other low expansion glasses, including Zerodur (TM), are based on SiO₂ and at least one alkaline metal oxide such as Na₂O, Li₂O or K₂O. Cordierite is based on MgO, Al₂O₃ and SiO₂.

[0033] As can be seen from the Table 1, suitable materials for the frame are the glass ceramic materials which have a Young's Modulus, E, of at least 60,000 MN/m². However, there are some ceramics which also meet the requirements.

[0034] As can be seen from Figure 2, the frame 10 is manufactured from a plurality of pieces of glass ceramic. In the preferred embodiment the glass ceramic material is Zerodur (TM). The separate parts of the frame 10 are connected by gluing, fritting (gluing at high temperature in which a glue material is placed between the pieces to be joined), fusion or by using bolts. The elongation of the frame 10 over time with temperature will thus be reduced by a factor of 200 with respect to normally used types of stainless steel.

[0035] The frame 10 may be constructed in any suitable way. In the preferred embodiment the frame 10 is made of three generally parallel plates including a central first plate 100 and two further plates 110, 120 which are positioned in spaced apart relationship to the central first plate 100 with one of their major surfaces facing a major surface of the central first plate 100.

[0036] Plates can be prone to vibrations and so the plates 100, 110, 120 are connected together using stiffener elements 130 which extend between an edge of one of the further plates 110, 120 and an edge of the central plate

100. In the preferred embodiment the stiffener elements 130 extend along the entire length of the edge of the plates (i.e. they are in the form of plates) but the required stiffness is achievable even if the stiffener elements 130 only extend between corners of the plates 100, 110, 120 for example they could be in the form of bars linking the plates.

[0037] Preferably the optical elements are mounted to the plates 100, 110, 120. Through holes 115, 135 in both the plates 100, 110, 120 and the stiffener elements 130 allow the projection beam PB to enter the frame 10 and also for the provision of utilities such as gas, air etc. to the positioning means of the optical elements and also for sensors and the like inside the frame 10. There may be removable access panels in the stiffener elements 130 and/or plates 100, 110, 120 to facilitate access to the optical elements.

[0038] The frame 10 has been described with reference to supporting optical elements and may also support components of various sensors to detect the position of the optical elements. However, the invention is equally applicable to a so-called "reference frame" of the projection system which supports components of the various sensors to detect the position of the optical elements separate from the support frame of the projection system as described above.

[0039] Whilst specific embodiments of the invention have been described above, it will be appreciated that the invention may be practiced otherwise than as described. The description is not intended to limit the invention.

Claims

1. A lithographic projection apparatus comprising:

- a radiation system for providing a projection beam of radiation;
- a support structure for supporting patterning means, the patterning means serving to pattern the projection beam according to a desired pattern;
- a substrate table for holding a substrate;
- a projection system for projecting the patterned beam onto a target portion of the substrate; and
- a frame supporting a plurality of optical elements of said projection system and/or components of sensors,

characterized in that said frame is made of a glass ceramic material with a coefficient of thermal expansion of less than or approximately equal to $0.1 \times 10^{-6} \text{ K}^{-1}$.

2. An apparatus according to claim 1, wherein said material is selected from the group containing Zerodur (TM), ULE (TM), Cordierite (TM), Astrosital (TM) and Clearceram-Z (TM).

3. An apparatus according to claim 1 or 2, wherein the coefficient of thermal expansion of said material is less than or approximately equal to $0.05 \times 10^{-6} \text{ K}^{-1}$.

4. An apparatus according to claim 1, 2 or 3, wherein said material has a Young's Modulus, E, of at least $60\,000 \text{ MN/m}^2$.

5. An apparatus according to any one of the preceding claims, wherein said frame comprises a first plate and at least one further plate, said plates being in spaced apart relationship and arranged such that surfaces of said plates face each other, said at least one further plate being attached to said first plate by stiffener elements thereby substantially to prevent flexing vibrations of said plates.

6. An apparatus according to claim 5, wherein said optical elements are attached to said plates.

7. An apparatus according to any one of the preceding claims, wherein said optical elements are mirrors.

8. An apparatus according to any one of the preceding claims, wherein said optical elements are independently mounted on said frame.

9. A device manufacturing method comprising the steps of:

- providing a substrate that is at least partially covered by a layer of radiation-sensitive material;
- providing a projection beam of radiation using a radiation system;
- using patterning means to endow the projection beam with a pattern in its cross-section;
- using a plurality of optical elements to project the patterned beam of radiation onto a target portion of the layer of radiation-sensitive material,
- measuring the position of said optical elements using sensors,

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- wherein said optical elements or said sensors are mounted on a frame, **characterized in that** said frame is made of a glass ceramic material with a coefficient of thermal expansion of less than or approximately equal to $0.1 \times 10^{-6} \text{ K}^{-1}$.

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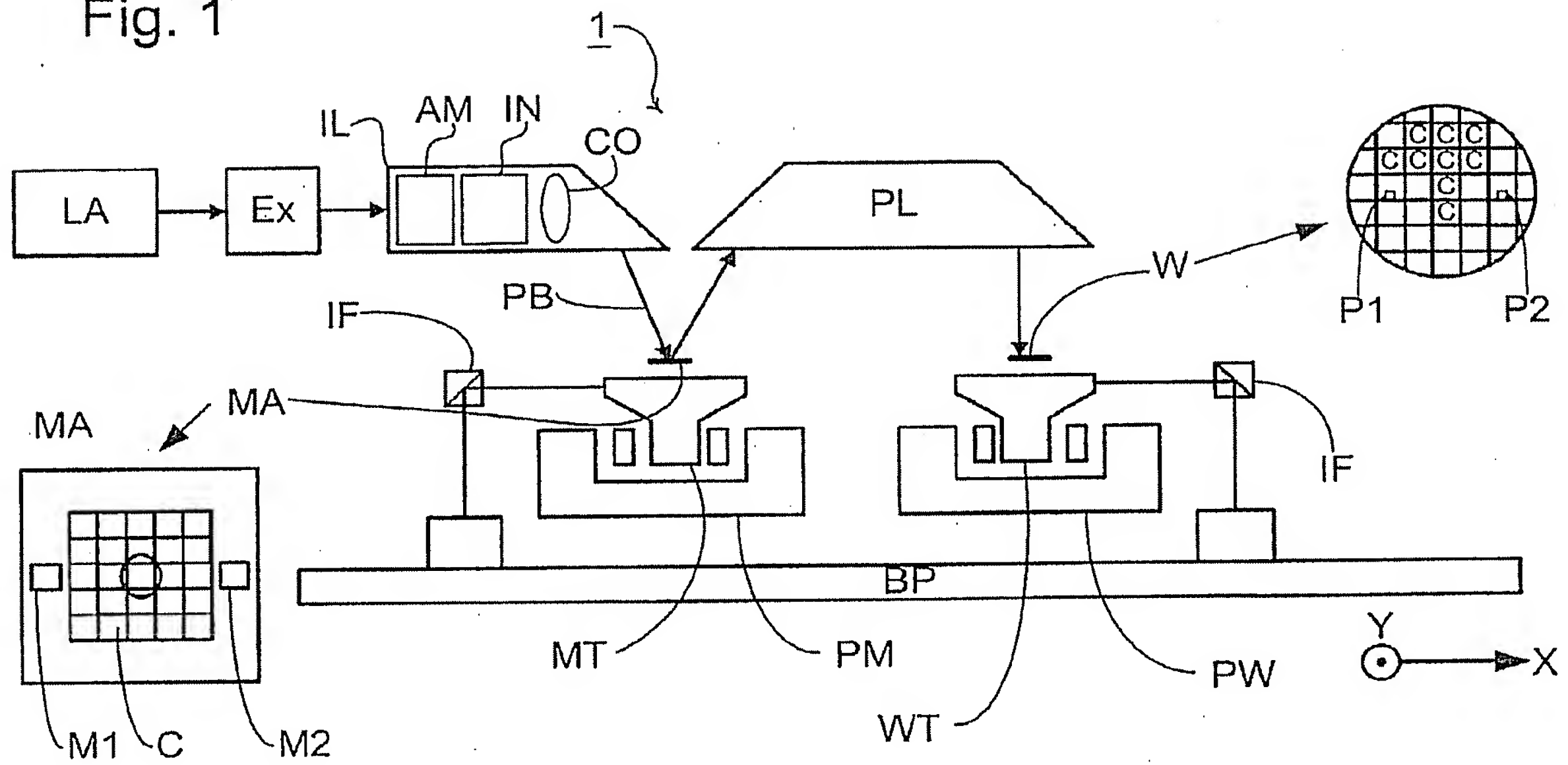
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Fig. 1



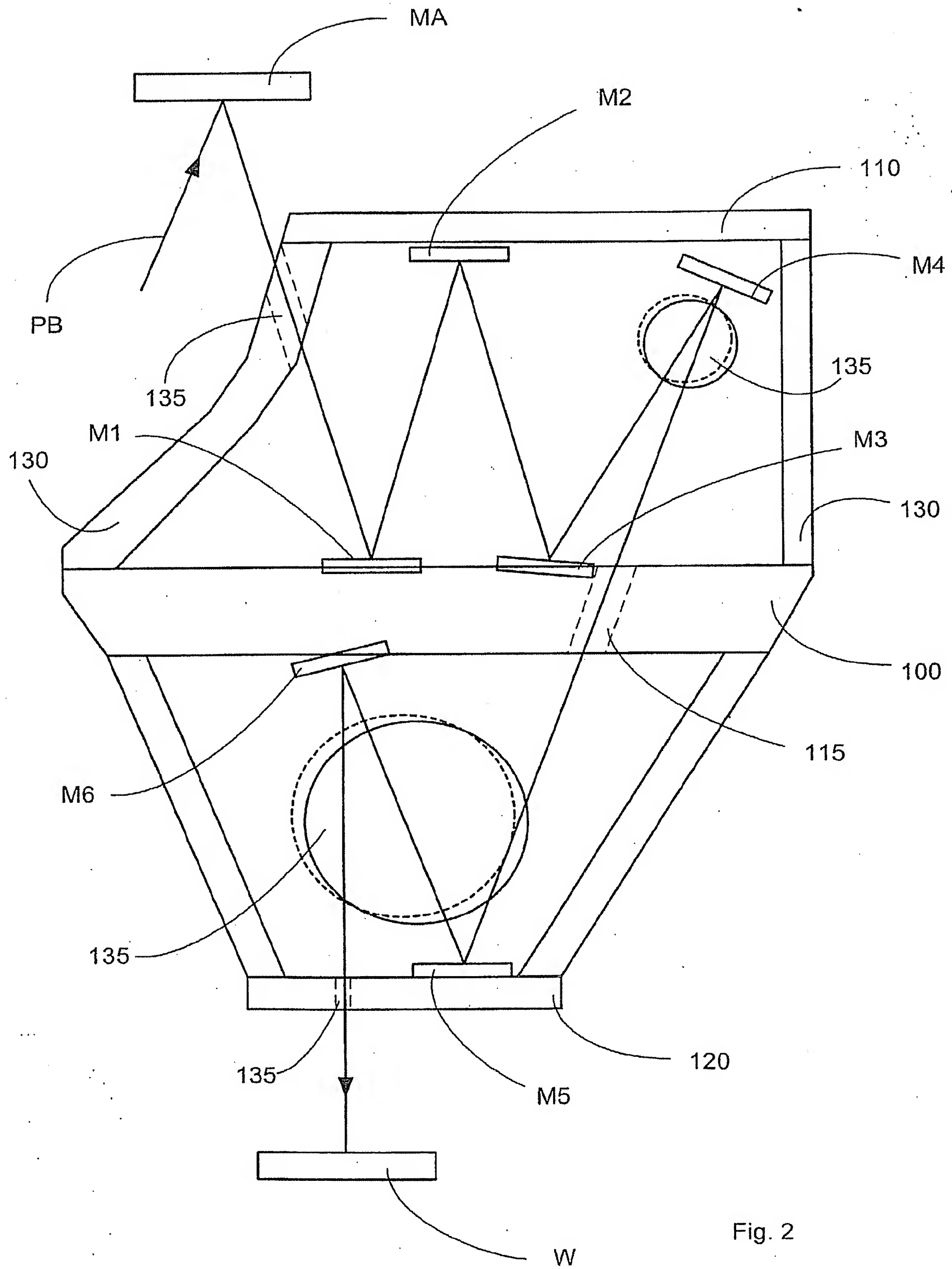
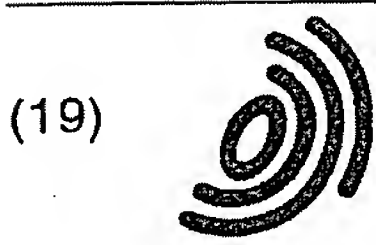


Fig. 2



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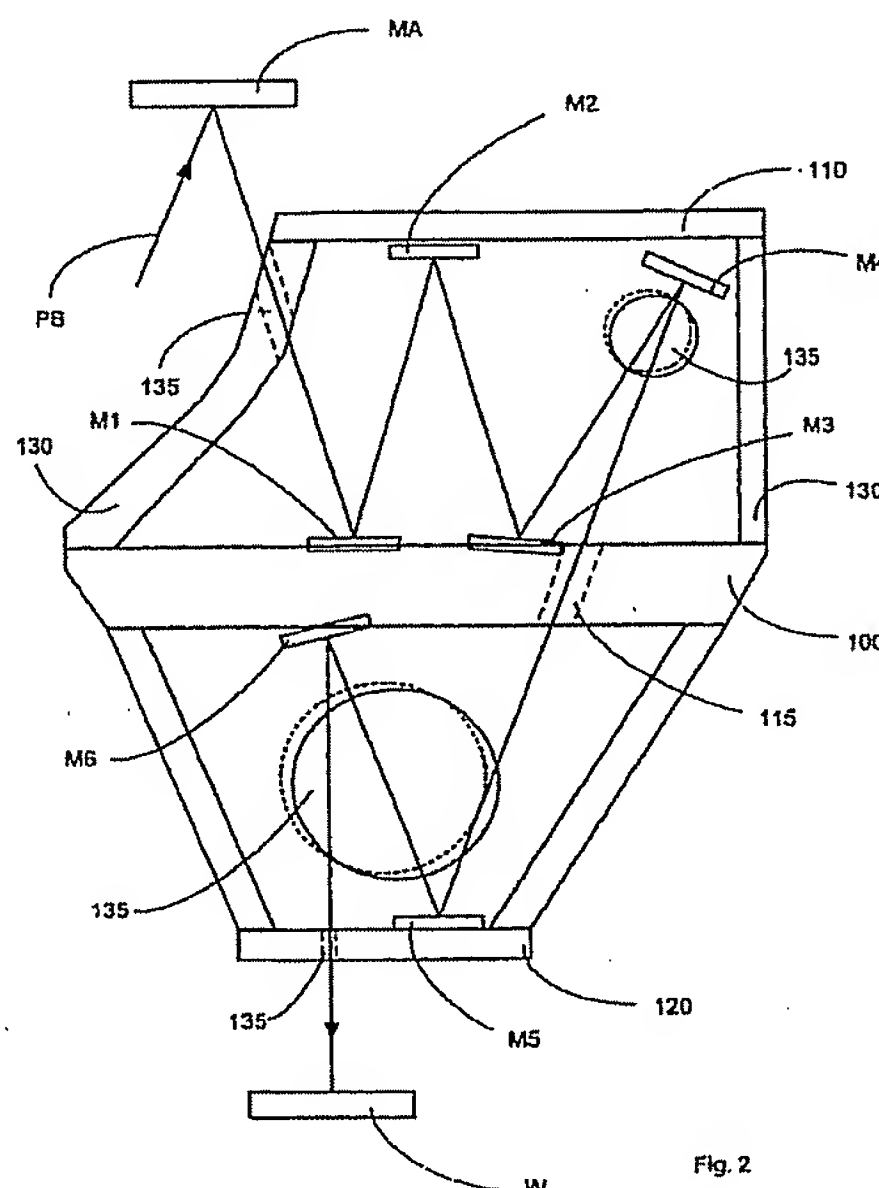
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(54) **Lithographic apparatus and device manufacturing method**

(57) A lithographic projection apparatus in which the projection system comprises a plurality of optical elements or sensors mounted on a frame. The frame is made of a glass ceramic material with a coefficient of thermal expansion of less than or approximately equal to $0.1 \times 10^{-6} \text{ K}^{-1}$ thereby avoiding the need for expensive cooling systems and/or predictive temperature compensation.





European Patent
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EUROPEAN SEARCH REPORT

Application Number
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| Category | Citation of document with indication, where appropriate, of relevant passages | Relevant to claim | CLASSIFICATION OF THE APPLICATION (Int.Cl.7) |
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| | | | G03F G02B |
| The present search report has been drawn up for all claims | | | |
| Place of search MUNICH | | Date of completion of the search 12 December 2003 | Examiner Hornung, A |
| <p>CATEGORY OF CITED DOCUMENTS</p> <p>X : particularly relevant if taken alone Y : particularly relevant if combined with another document of the same category A : technological background O : non-written disclosure P : intermediate document</p> <p>T : theory or principle underlying the invention E : earlier patent document, but published on, or after the filing date D : document cited in the application L : document cited for other reasons & : member of the same patent family, corresponding document</p> | | | |

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**ANNEX TO THE EUROPEAN SEARCH REPORT
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